Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/777,189	WAKAYAMA ET AL.
Examiner	Art Unit

2814

Hoai v. Pham

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	SEAR	CHED	
Class	Subclass	Date	Examiner
257	620	5/12/2005	HP
257	758	5/12/2005	HP
257	759	5/12/2005	HP
257	760	5/12/2005	HP
257	774	5/12/2005	НР

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEAI (INCLUDING S	RCH NOTES SEARCH STRATEGY)
	DATE	EXMR
East search	5/12/2005	НР
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